

**Search Notes**

Application/Control No.

10/561,916

Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

MAEDA ET AL.

Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
see	upad srch	5/4/2010	PL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Discussed allowability- reviewed all prior art (including STIC search) with Jean Vollano (QAS,chem expert)	1/15/2010	PL
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	4/16/2010	PL
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	5/4/2010	PL
Interference search: EAST: USPGUBS and UPAD	5/4/2010	PL
inventor name search updated EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE	5/4/2010	PL